Special Issue

Precision Measurement Technology

Message from the Guest Editors

In the current digital era of rapid technological advancement and increasing demand for accuracy and precision in manufacturing, precision measurement systems and technologies play a critical role in innovation across multiple research fields. Measurements, from the nanoscale to large scales, underpin the fundamental accuracy and reliability of scientific discoveries and modern technologies. This issue invites contributions that investigate advances in measurement techniques, instrumentation, data processing, calibration, system integration, etc. Topics of interest include, but are not limited to, innovations in sensor technologies, advanced signal processing algorithms, measurement characterisation, uncertainty evaluation, artificial intelligence-driven measurement systems, and interdisciplinary applications of precision metrology. This Special Issue seeks to foster collaboration by disseminating related research, addressing current challenges, and inspiring future directions in the field of precision measurement.

Guest Editors

Dr. Mohammed A. Isa

Dr. Mingyu Liu

Prof. Dr. Samanta Piano

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Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

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